

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/719,570	SARFATY, MOSHE	
			Examiner	Art Unit	Page 1 of 1
			Evan Pert	2829	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
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	V	
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